

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO.:  CHUDоба, T. 1 PCT		SERIAL NO.: <b>10/532630</b>		
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: <b>Thomas Chudoba et al.</b>				
				FILING DATE: <b>Sept. 7 2005</b> GROUP: <b>2855</b>				
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
JD	AA	5,051,594	09/1991	<del>Fumihiko et al.</del> <b>Tsuda et al.</b>				
JD	AB	4,157,818	06/1979	Key				
JD	AC	3,201,980	08/1965	Webb				
JD	AD	5,343,748	09/1994	<del>Keasey, et al.</del> <b>Mozgowiec et al.</b>				
JD	AE	2,573,286	10/1951	Baker, et al.				
	AF							
	AG							
	AH							
<b>FOREIGN PATENT DOCUMENTS</b>								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
JD	AL	WO 02 16907	02/2002	PCT				
JD	AM	WO 99 46576	09/1999	PCT				
	AN							
	AO							
	AP							
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
JD	AQ		"Microscratch and Load Relaxation Tests for Ultra-Thin Films" - Wu T. W. Journal of Materials Research, New York, NY, U.S., Vol. 6, no. 2, pages 407-426 February 1991					
JD	AR		International Search Report					
	AS							
EXAMINER <b>/Jonathan Dunlap/</b>				DATE CONSIDERED <b>03/02/2007</b>				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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1966-2005 Our 39<sup>th</sup> Year

FORM PTO-1449  
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.:

CHUDоба, et al PCT

SERIAL NO.:

10/532,630

## LIST OF REFERENCES CITED BY APPLICANT

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